

# DATA SHEET

## **HSTL16918**

9-bit to 18-bit HSTL-to-LVTTL  
memory address latch

Product data

2001 Jun 16

9-bit to 18-bit HSTL-to-LVTTL memory address latch

HSTL16918

FEATURES

- Inputs meet JEDEC HSTL Std. JESD 8–6, and outputs meet Level III specifications
- ESD classification testing is done to JEDEC Standard JESD22. Protection exceeds 2000 V to HBM per method A114.
- Latch-up testing is done to JEDEC Standard JESD78, which exceeds 100 mA.
- Packaged in 48-pin plastic thin shrink small outline package (TSSOP48)

DESCRIPTION

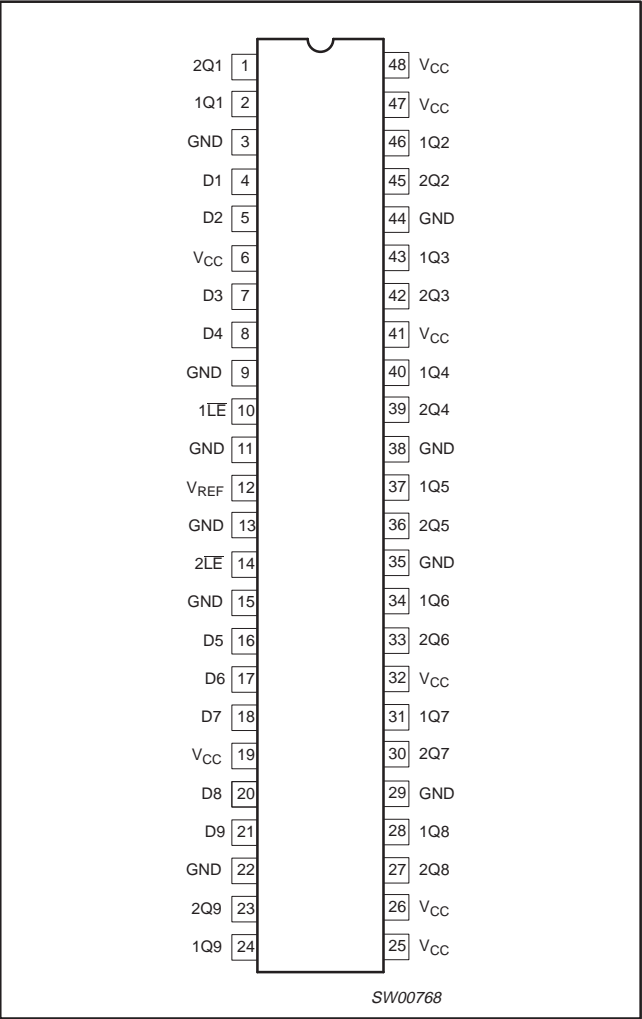
The HSTL16918 is a 9-bit to 18-bit D-type latch designed for 3.15 to 3.45 V  $V_{CC}$  operation. The D inputs accept HSTL levels and the Q outputs provide LVTTL levels.

The HSTL16918 is particularly suitable for driving an address bus to two banks of memory. Each bank of nine outputs is controlled with its own latch-enable ( $\overline{LE}$ ) input.

Each of the nine D inputs is tied to the inputs of two D-type latches that provide true data (Q) at the outputs. While  $\overline{LE}$  is LOW the Q outputs of the corresponding nine latches follow the D inputs. When  $\overline{LE}$  is taken HIGH, the Q outputs are latched at the levels set up at the D inputs.

The HSTL16918 is characterized for operation from 0 to +70 °C.

PIN CONFIGURATION



ORDERING INFORMATION

| PACKAGES   | TEMPERATURE RANGE | ORDER CODE   | DWG NUMBER |
|--|-------------------|--------------|------------|
| 48-pin plastic thin shrink small outline package (TSSOP48) | 0 to +70 °C       | HSTL16918DGG | SOT362-1   |

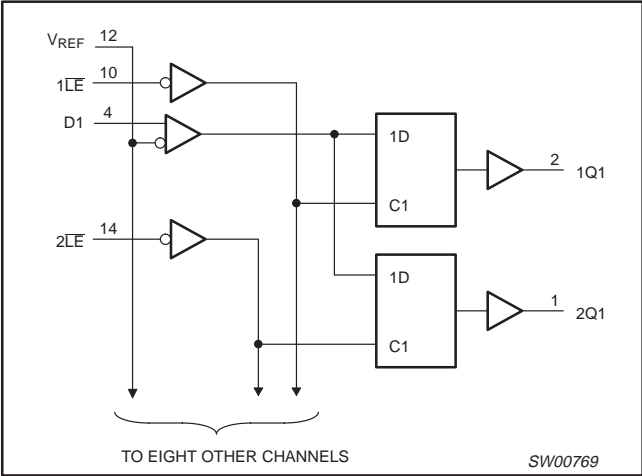
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HSTL16918

PIN DESCRIPTION

| PIN                                  | SYMBOL  | FUNCTION          |
|--------------------------------------|---------|-------------------|
| 4, 5, 7, 8, 16, 17, 18, 20, 21       | D[1–9]  | Inputs            |
| 2, 46, 43, 40, 37, 34, 31, 28, 24    | 1Q[1–9] | Outputs           |
| 1, 45, 42, 39, 36, 33, 30, 27, 23    | 2Q[1–9] |                   |
| 10                                   | 1LE     | Latch enable      |
| 14                                   | 2LE     |                   |
| 12                                   | VREF    | Reference voltage |
| 6, 19, 25, 26, 32, 41, 47, 48        | VCC     | Supply voltage    |
| 3, 9, 11, 13, 15, 22, 29, 35, 38, 44 | GND     | Ground            |

LOGIC DIAGRAM (positive logic)



FUNCTION TABLE

| INPUTS |   | OUTPUT<br>Q |
|--------|---|-------------|
| LE     | D |             |
| L      | H | H           |
| L      | L | L           |
| H      | X | $Q_0^1$     |

**NOTE:**  
1. Output level before the indicated steady-state input conditions were established.

## 9-bit to 18-bit HSTL-to-LVTTL memory address latch

## HSTL16918

**ABSOLUTE MAXIMUM RATINGS<sup>1</sup>**

Over operating free-air temperature range (unless otherwise noted).

| SYMBOL        | PARAMETER                                       | CONDITIONS                  | RATING                 | UNIT |
|---------------|---|-----------------------------|------------------------|------|
| $V_{CC}$      | Supply voltage range                            |                             | -0.5 to +4.6           | V    |
| $V_I$         | Input voltage range <sup>2</sup>                |                             | -0.5 to $V_{CC} + 0.5$ | V    |
| $V_O$         | Output voltage range <sup>2</sup>               |                             | -0.5 to $V_{CC} + 0.5$ | V    |
| $I_{IK}$      | Input clamp current                             | $V_I < 0$                   | -50                    | mA   |
| $I_{OK}$      | Output clamp current <sup>3</sup>               | $V_O < 0$ or $V_O > V_{CC}$ | $\pm 50$               | mA   |
| $I_O$         | Continuous output current                       | $V_O = 0$ to $V_{CC}$       | $\pm 50$               | mA   |
|               | Continuous current through each $V_{CC}$ or GND |                             | $\pm 100$              | mA   |
| $\theta_{JA}$ | Package thermal impedance <sup>4</sup>          |                             | 89                     | °C/W |
| $T_{stg}$     | Storage temperature range                       |                             | -65 to +150            | °C   |

**NOTES:**

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- This current flows only when the output is in the high state and  $V_O > V_{CC}$ .
- The package thermal impedance is calculated in accordance with JESD 51.

**RECOMMENDED OPERATING CONDITIONS<sup>1</sup>**

| SYMBOL    | PARAMETER                            |            | LIMITS             |      |                    | UNIT |
|-----------|--------------------------------------|------------|--------------------|------|--------------------|------|
|           |                                      |            | Min                | Nom  | Max                |      |
| $V_{CC}$  | Supply voltage                       |            | 3.15               |      | 3.45               | V    |
| $V_{REF}$ | Reference voltage                    |            | 0.68               | 0.75 | 0.9                | V    |
| $V_I$     | Input voltage                        |            | 0                  |      | 1.5                | V    |
| $V_{IH}$  | AC high-level input voltage          | All inputs | $V_{REF} + 200$ mV |      |                    | V    |
| $V_{IL}$  | AC low-level input voltage           | All inputs |                    |      | $V_{REF} - 200$ mV | V    |
| $V_{IH}$  | DC high-level input voltage          | All inputs | $V_{REF} + 100$ mV |      |                    | V    |
| $V_{IL}$  | DC low-level input voltage           | All inputs |                    |      | $V_{REF} - 100$ mV | V    |
| $I_{OH}$  | High-level output current            |            |                    |      | -24                | mA   |
| $I_{OL}$  | Low-level output current             |            |                    |      | 24                 | mA   |
| $T_{amb}$ | Operating free-air temperature range |            | 0                  |      | +70                | °C   |

**NOTE:**

- All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation.

## 9-bit to 18-bit HSTL-to-LVTTL memory address latch

## HSTL16918

**ELECTRICAL CHARACTERISTICS**

Over recommended operating free-air temperature range (unless otherwise noted).

| SYMBOL   | PARAMETER      | TEST CONDITIONS   | LIMITS |                  |         | UNIT          |
|----------|----------------|---|--------|------------------|---------|---------------|
|          |                |   | Min    | Typ <sup>1</sup> | Max     |               |
| $V_{IK}$ |                | $V_{CC} = 3.15\text{ V}; I_I = -18\text{ mA}$                       |        |                  | -1.2    | V             |
| $V_{OH}$ |                | $V_{CC} = 3.15\text{ V}; I_{OH} = -24\text{ mA}$                    | 2.4    |                  |         | V             |
| $V_{OL}$ |                | $V_{CC} = 3.15\text{ V}; I_{OL} = 24\text{ mA}$                     |        |                  | 0.5     | V             |
| $I_I$    | Control inputs | $V_{CC} = 3.45\text{ V}; V_I = 0\text{ or }1.5\text{ V}$            |        |                  | $\pm 5$ | $\mu\text{A}$ |
|          | Data inputs    | $V_{CC} = 3.45\text{ V}; V_I = 0\text{ or }1.5\text{ V}$            |        |                  | $\pm 5$ | $\mu\text{A}$ |
|          | $V_{REF}$      | $V_{CC} = 3.45\text{ V}; V_{REF} = 0.68\text{ V or }0.9\text{ V}$   |        |                  | 90      | $\mu\text{A}$ |
| $I_{CC}$ |                | $V_{CC} = 3.45\text{ V}; V_I = 0\text{ or }1.5\text{ V}$            |        | 50               | 100     | mA            |
| $C_I$    | Control inputs | $V_{CC} = 0\text{ or }3.3\text{ V}; V_I = 0\text{ or }3.3\text{ V}$ |        | 2                |         | pF            |
|          | Data inputs    | $V_{CC} = 0\text{ or }3.3\text{ V}; V_I = 0\text{ or }3.3\text{ V}$ |        | 2.5              |         | pF            |
| $C_O$    | Outputs        | $V_{CC} = 0\text{ V}; V_O = 0\text{ V}$                             |        | 4                |         | pF            |

**NOTE:**1. All typical values are at  $V_{CC} = 3.3\text{ V}; T_{amb} = 25\text{ }^\circ\text{C}$ .**TIMING REQUIREMENTS**

Over recommended operating free-air temperature range (unless otherwise noted).

| SYMBOL    | PARAMETER                             | TEST CONDITIONS                              | $V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$ |     | UNIT |
|-----------|---------------------------------------|--|---|-----|------|
|           |                                       |  | Min                                       | Max |      |
| $t_w$     | Pulse duration                        | $\overline{LE}$ LOW (Figure 1)               | 3   |     | ns   |
| $t_{su}$  | Setup time                            | D before $\overline{LE} \uparrow$ (Figure 2) | 2   |     | ns   |
| $t_h$     | Hold time                             | D after $\overline{LE} \uparrow$ (Figure 2)  | 1   |     | ns   |
| $t_{ldr}$ | Data race condition time <sup>1</sup> | D after $\overline{LE} \downarrow$           |   | 0   | ns   |

**NOTE:**1. This is the maximum time after  $\overline{LE}$  switches LOW that the data input can return to the latched state from the opposite state without producing a glitch on the output.**SWITCHING CHARACTERISTICS**Over recommended operating free-air temperature range;  $V_{REF} = 0.75\text{ V}$ .

| SYMBOL   | PARAMETER                    | FROM (INPUT)    | TO (OUTPUT) | $V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$ |     | UNIT |
|----------|------------------------------|-----------------|-------------|---|-----|------|
|          |                              |                 |             | Min                                       | Max |      |
| $t_{pd}$ | Propagation delay (Figure 3) | D               | Q           | 1.9                                       | 3.4 | ns   |
|          |                              | $\overline{LE}$ | Q           | 1.9                                       | 4.2 | ns   |

**SIMULTANEOUS SWITCHING CHARACTERISTICS**Over recommended operating free-air temperature range;  $V_{REF} = 0.75\text{ V}$ 

| SYMBOL   | PARAMETER   | FROM (INPUT)    | TO (OUTPUT) | $V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$ |     | UNIT |
|----------|---|-----------------|-------------|---|-----|------|
|          |   |                 |             | Min                                       | Max |      |
| $t_{pd}$ | Propagation delay; all outputs switching (Figure 3) | D               | Q           | 1.9                                       | 4.4 | ns   |
|          |   | $\overline{LE}$ | Q           | 1.9                                       | 5.2 | ns   |

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HSTL16918

## VOLTAGE WAVEFORMS

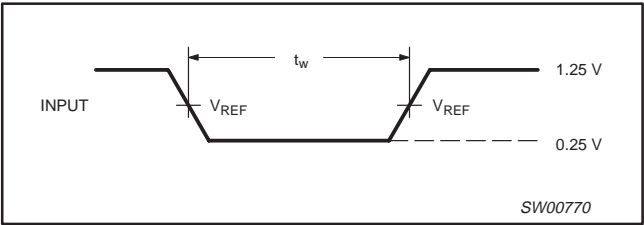


Figure 1. Pulse duration

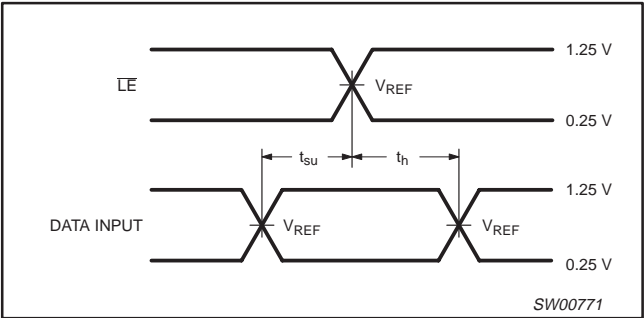


Figure 2. Setup and Hold times

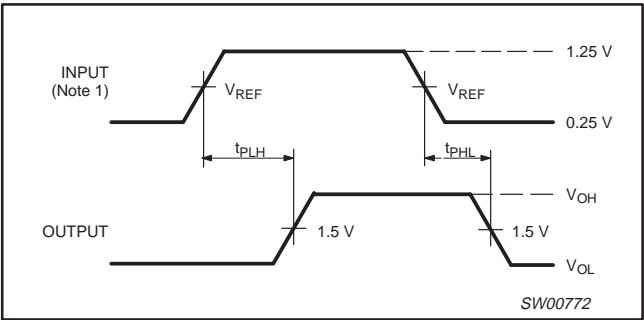
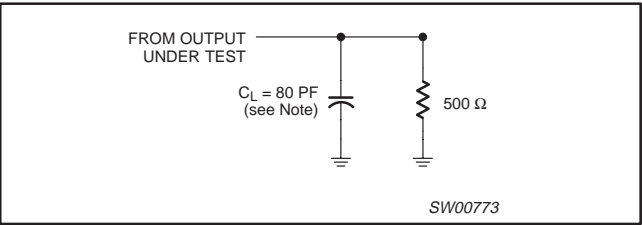


Figure 3. Propagation delay times

### NOTES:

1. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 1 \text{ ns}$ ,  $t_f \leq 1 \text{ ns}$ .
2. The outputs are measured one at a time with one transition per measurement.
3.  $t_{PHL}$  and  $t_{PLH}$  are the same as  $t_{pd}$ .

## LOAD CIRCUIT



NOTE:  $C_L$  includes probe and jig capacitance.

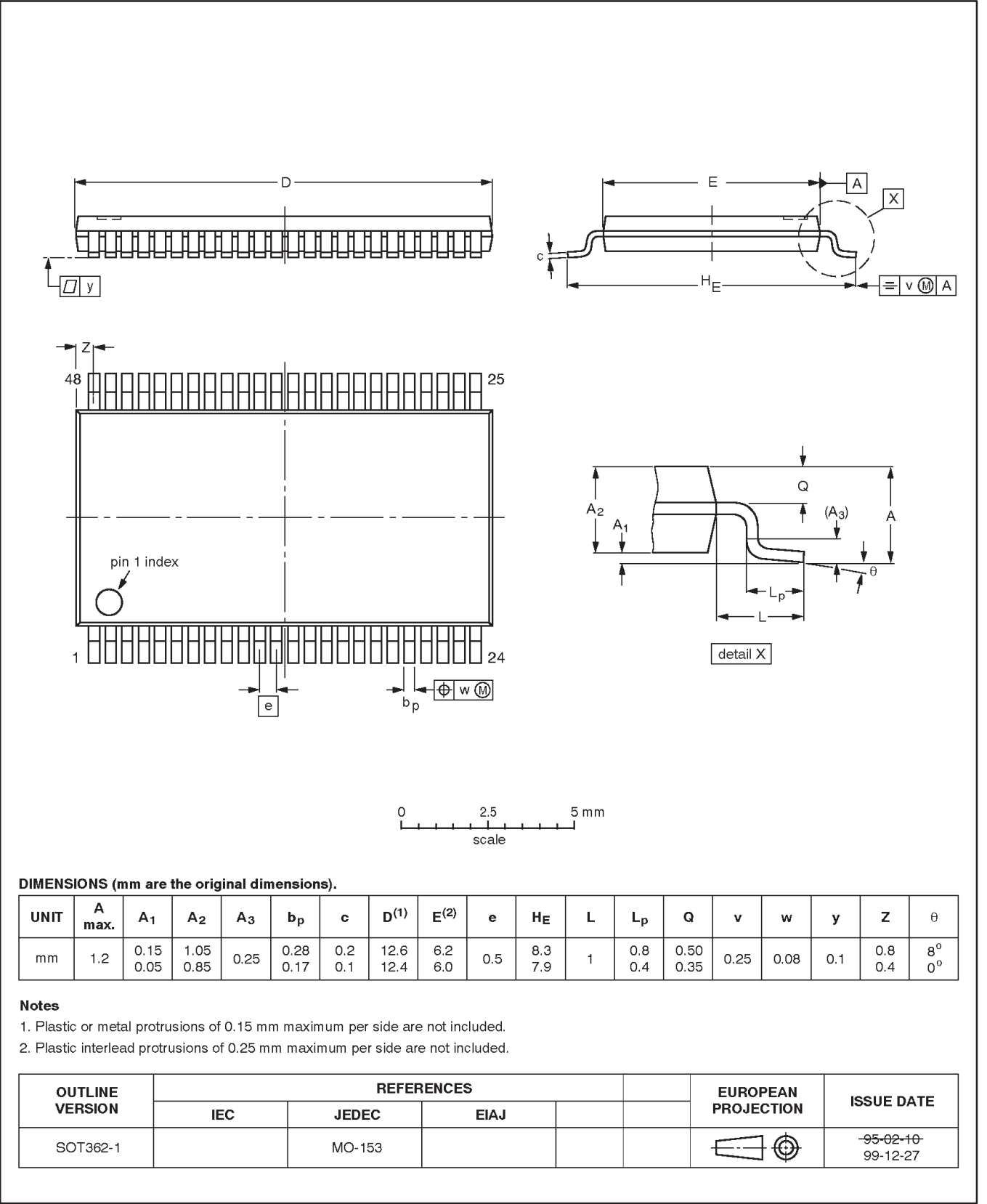
Figure 4. Load circuit

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HSTL16918

TSSOP48: plastic thin shrink small outline package; 48 leads; body width 6.1 mm

SOT362-1



## 9-bit to 18-bit HSTL-to-LVTTL memory address latch

HSTL16918

## Data sheet status

| Data sheet status <sup>[1]</sup> | Product status <sup>[2]</sup> | Definitions  |
|----------------------------------|-------------------------------|--|
| Objective data                   | Development                   | This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.  |
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[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.

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**Limiting values definition** — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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